

**Search Notes**

Application/Control No.

10/766,646

Examiner

Eric B. Chen

Applicant(s)/Patent under  
Reexamination

LEE, HEON

Art Unit

1765

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor search (PALM)	9/13/2005	EC
EAST (all databases) - see search history printout	9/14/2005	EC
216/2, 11-13, 33-36, 44, 52 54, 67, 79, 81, 88-91, 96; 264/320; 249/115, 118, 114.1 (text search only) (consulted A. Alanko, B. Tran)	9/15/2005	EC